



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: 10/582,340

In re Application of:

Toshifumi YOKOYAMA et al

Filed: June 9, 2006

For: DISPLAY UNIT AND SCANNING METHOD THEREOFR

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, Virginia 22313-1450

Sir:

Pursuant to 37 C.F.R. 1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached Form PTO-1449. A copy of the foreign references listed on Form PTO-1449 is attached.

EP Patent 1,292,134 is the English-language equivalent of Japanese Published Patent Appln. No. 2003-98476 discussed at page 1 of the specification.

U.S. Patent No. 5,044,710 is the U.S. equivalent of Japanese Published Patent Appln. No. Hei.2-259617 cited in the International Search Report.

Serial No. New Appln. 10/582,340

The relevancy of Japanese Published Patent Applns. Nos. Sho. 64-13114 (Abstract 01-013114), Sho.57-52031 and Sho.50-26305 are indicated in the International Search Report. A Statement of Relevancy with regard to Appln. No. 50-26305 is provided herewith.

The above information is presented so that the Patent and Trademark Office may, in the first instance, determine any materiality thereof to the claimed invention. See 37 C.F.R. 1.104(a) and 1.106(b) concerning the PTO duty to consider and use any such information. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that this reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

Respectfully submitted,

STEPTOE & JOHNSON LLP

Hugurt 1, 2006

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Form PTO-144 (Modified)	= 1115			Attorney's Docket No. 28951.1177		Application No. 10/582,340			
Information Disclosure Statement			Applicant	Applicant Toshifumi YOKOYAMA et al					
(Use several sheets if necessary)		1 0	Filing Date June 9, 2006		Group Art Unit 2872				
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U.S. Patent Documents									
Examiner Initial	Desig. ID	Patent	Issue Date	Pater	ntee	Class	Subclass	Filing Date If Appropriate	
/JP/	AA	5,044,710	9/3/1991	Iwai et al		359	217		
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner	Desig.	Document	Publication	Country or			Translation	
Initia <u>l</u>	ID	Number	Date	Patent Office	Class	Subclass	Yes	No
/JP/	AC	1,292,134A2	03/2003	Europe			-	
/JP/	AD	1,292,134A3	08/2004	Europe				
/JP/	AE	01-013114	01/1989	Japan			Abstract	
JP/-	AF	57-52031	03/1982	Japan			Abstract	
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(Other Documents (include Author, Title, Date, and Place of Publication)					
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	AO					
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Examiner Signature	/James Phan/	Date Considered	07/30/2008
EXAMINER: Initials citati		ot in conformance and a	not considered. Include copy of this form with